

### General Description

- Latest advanced trench technology
- Low  $R_{DS(ON)}$
- High Current Capability
- RoHS and Halogen-Free Compliant

### Product Summary

$V_{DS}$	-30V
$I_D$ (at $V_{GS}=-10V$ )	-36A
$R_{DS(ON)}$ (at $V_{GS}=-10V$ )	< 7.8mΩ
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$ )	< 12.3mΩ

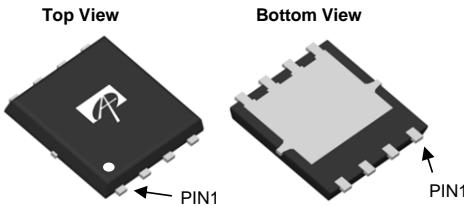
### Applications

- Notebook AC-in load switch
- Battery protection charge/discharge

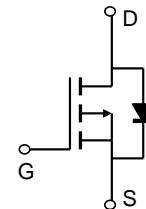
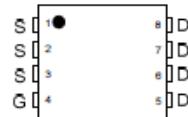
100% UIS Tested  
100%  $R_g$  Tested



**DFN5x6**



**Top View**



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AONS21357	DFN 5x6	Tape & Reel	3000

### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 25$	V
Continuous Drain Current <sup>G</sup>	$I_D$	-36	A
$T_C=100^\circ C$		-36	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-144	
Continuous Drain Current	$I_{DSM}$	-21	A
$T_A=70^\circ C$		-17	
Avalanche Current <sup>C</sup>	$I_{AS}$	39	A
Avalanche energy $L=0.1\text{mH}$ <sup>C</sup>	$E_{AS}$	76	mJ
Power Dissipation <sup>B</sup>	$P_D$	48	W
$T_C=100^\circ C$		19	
Power Dissipation <sup>A</sup>	$P_{DSM}$	5.0	W
$T_A=70^\circ C$		3.2	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{θJA}$	20	25	°C/W
Maximum Junction-to-Ambient <sup>A/D</sup>		45	55	°C/W
Maximum Junction-to-Case	$R_{θJC}$	2.1	2.6	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 25\text{V}$			-5	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	-1.3	-1.7	-2.3	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-20\text{A}$ $T_J=125^\circ\text{C}$		6.3	7.8	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-20\text{A}$		8.6	10.7	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-20\text{A}$		9.8	12.3	$\text{S}$
$V_{SD}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
$I_S$	Maximum Body-Diode Continuous Current <sup>G</sup>				-36	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		2830		pF
$C_{oss}$	Output Capacitance			430		pF
$C_{rss}$	Reverse Transfer Capacitance			365		pF
$R_g$	Gate resistance	$f=1\text{MHz}$		14	28	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-20\text{A}$		50	70	nC
$Q_g(4.5\text{V})$	Total Gate Charge			25	35	nC
$Q_{gs}$	Gate Source Charge			9		nC
$Q_{gd}$	Gate Drain Charge			12		nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		12.5		ns
$t_r$	Turn-On Rise Time			18		ns
$t_{D(off)}$	Turn-Off DelayTime			125		ns
$t_f$	Turn-Off Fall Time			66		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=-20\text{A}, di/dt=500\text{A}/\mu\text{s}$		62		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=-20\text{A}, di/dt=500\text{A}/\mu\text{s}$		32		nC

A. The value of  $R_{\text{BJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{BJA}} \leq 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

D. The  $R_{\text{BJA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{BJC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300  $\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink k, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

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### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

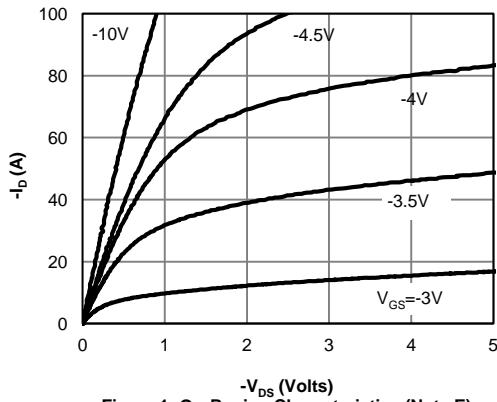


Figure 1: On-Region Characteristics (Note E)

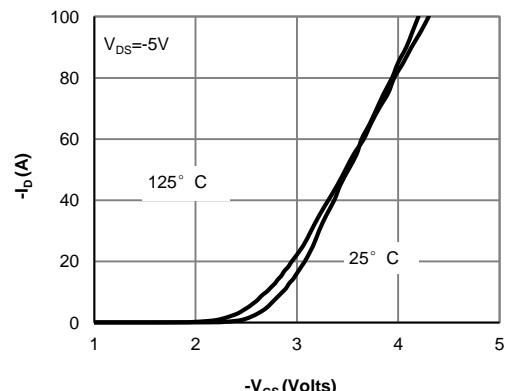


Figure 2: Transfer Characteristics (Note E)

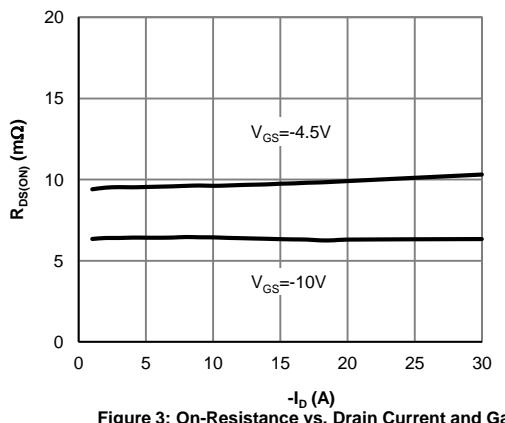


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

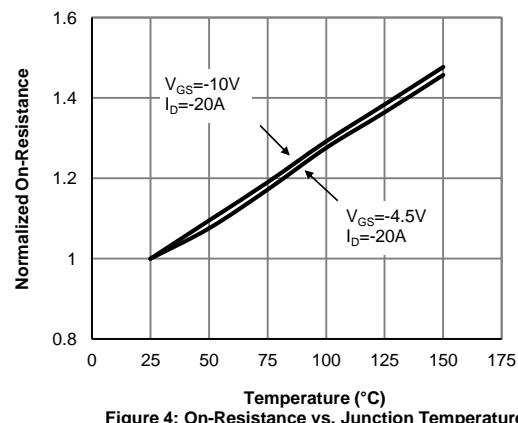


Figure 4: On-Resistance vs. Junction Temperature (Note E)

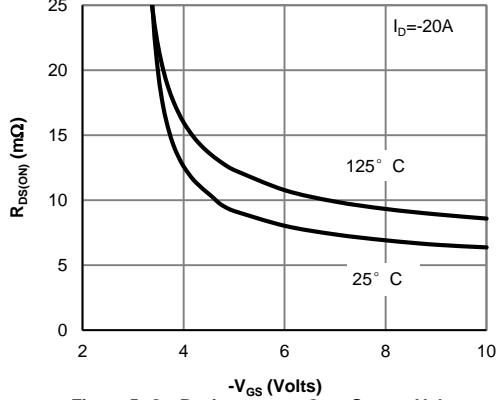


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

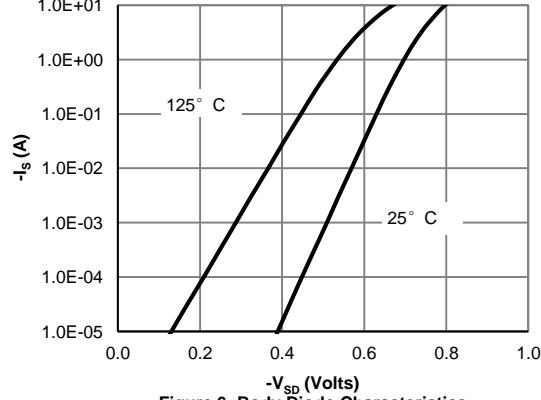


Figure 6: Body-Diode Characteristics (Note E)

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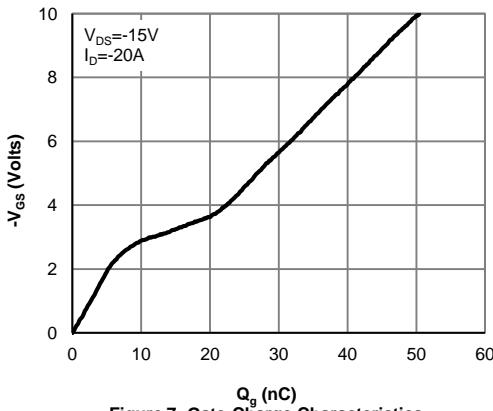


Figure 7: Gate-Charge Characteristics

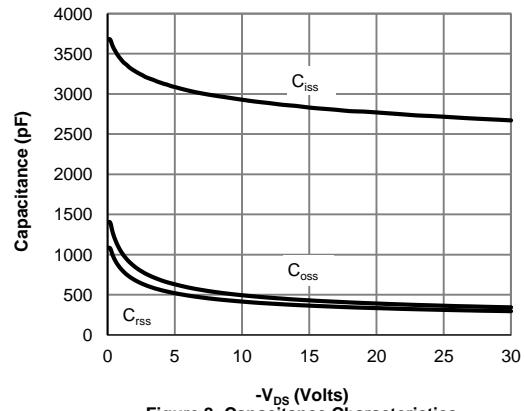


Figure 8: Capacitance Characteristics

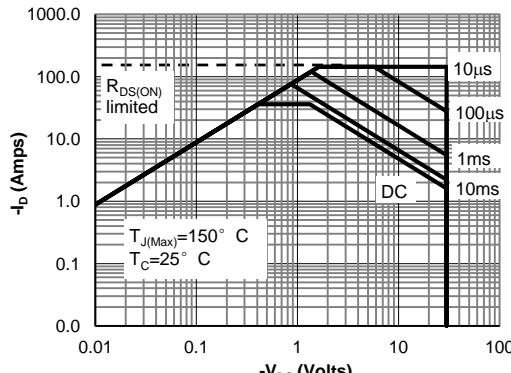


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

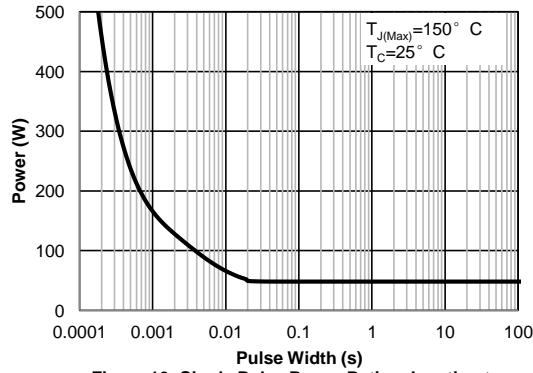


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

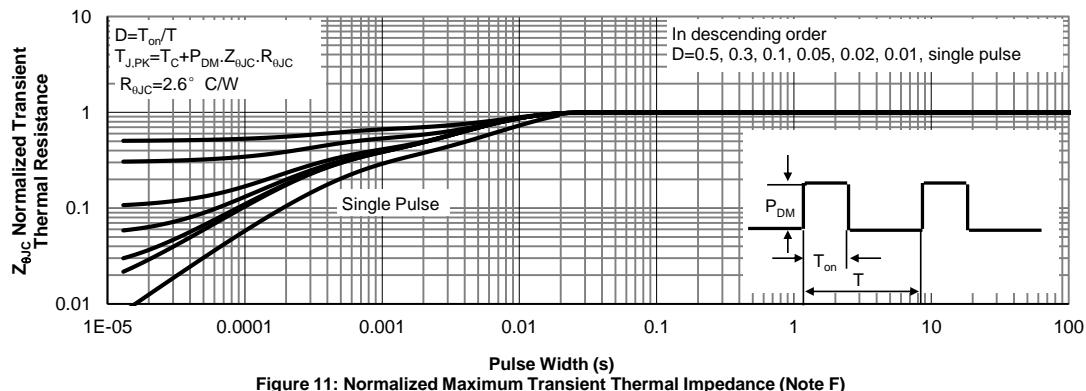


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

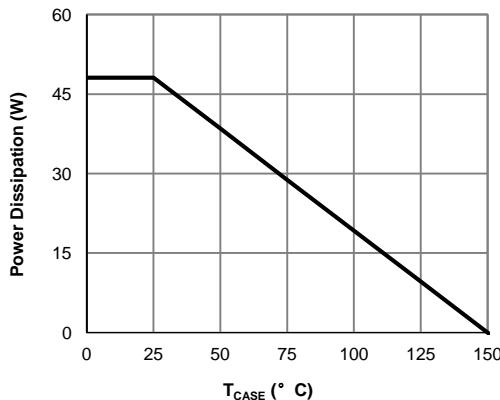

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

Figure 12: Power De-rating (Note F)

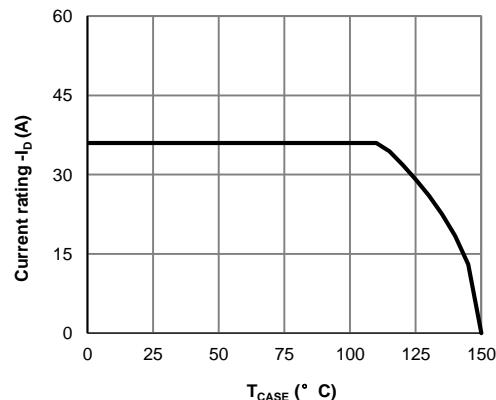


Figure 13: Current De-rating (Note F)

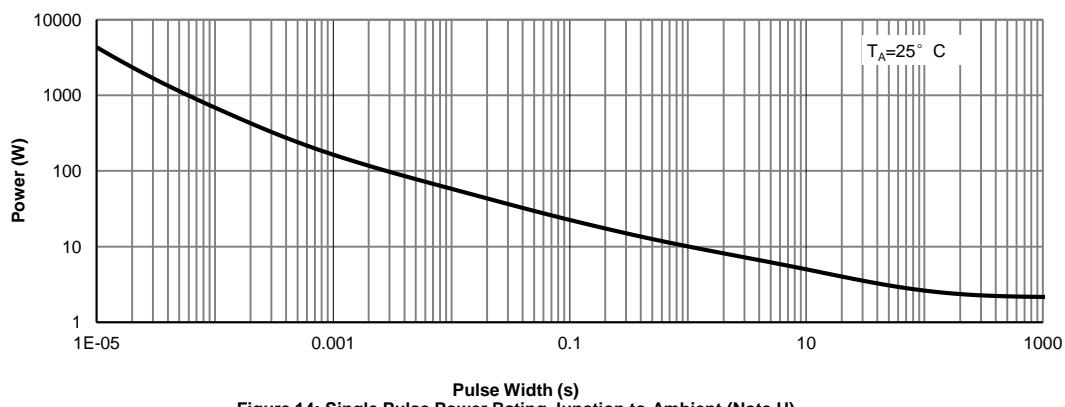


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

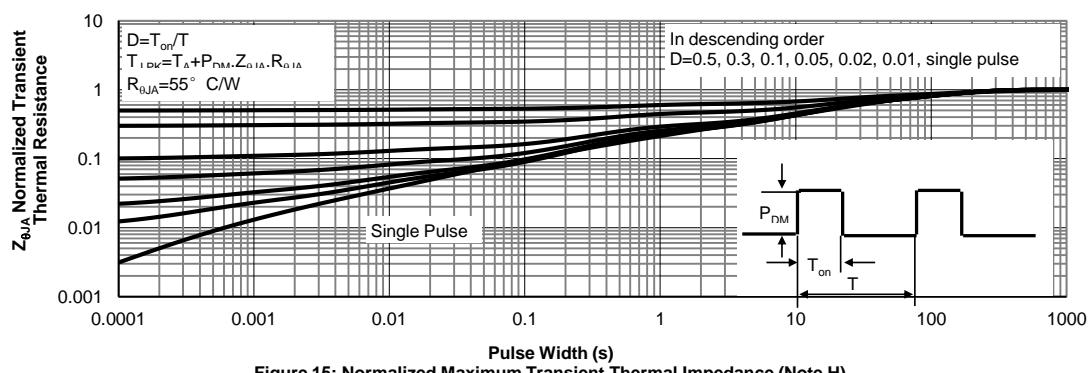
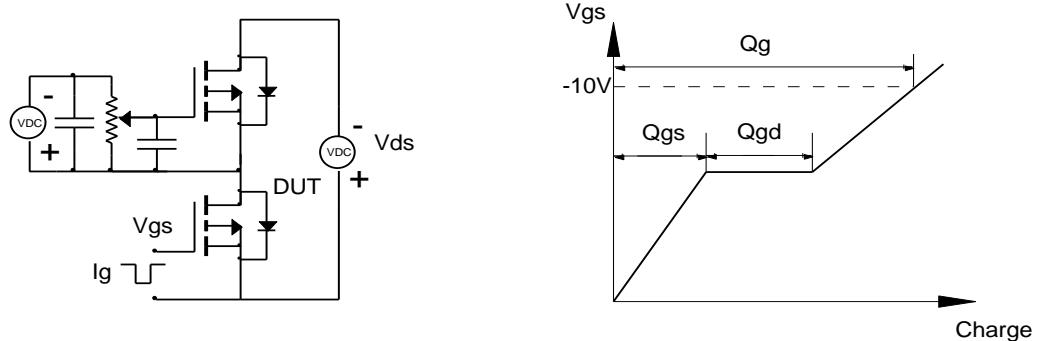


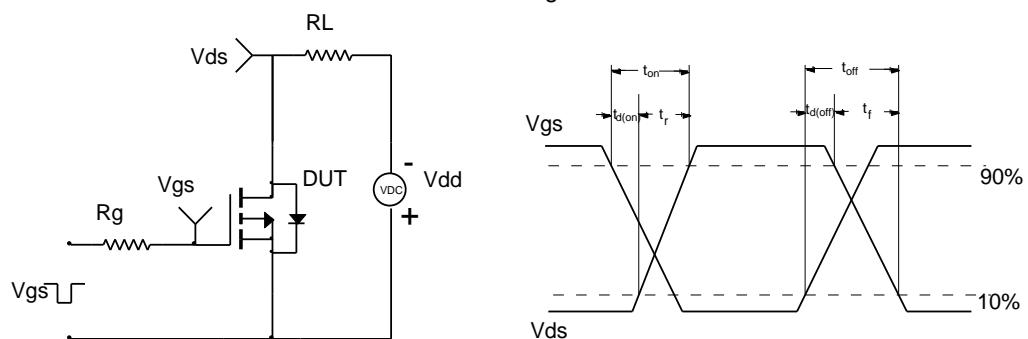
Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)



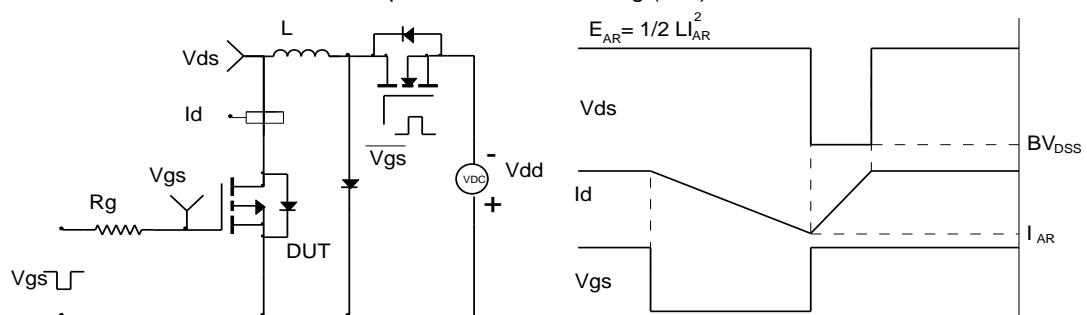
Gate Charge Test Circuit &amp; Waveform



Resistive Switching Test Circuit &amp; Waveforms



Unclamped Inductive Switching (UIS) Test Circuit &amp; Waveforms



Diode Recovery Test Circuit &amp; Waveforms

